

VNT008A/9A, VNS008A/9A

N-Channel Enhancement Mode Transistors

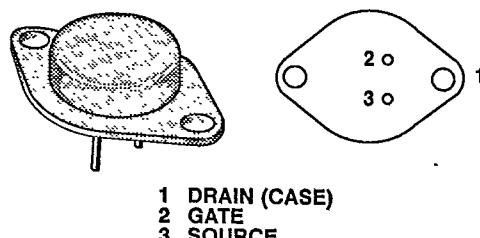
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PRODUCT SUMMARY

PART NUMBER	$V_{(BR)DSS}$ (V)	$r_{DS(ON)}$ (Ω)	I_D (A)
VNT008A	650	1.5	5.77
VNS008A	600	1.5	5.77
VNT009A	650	2.0	5.0
VNS009A	600	2.0	5.0

TO-204AA (TO-3)

BOTTOM VIEW

**ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	VNT 008A	VNS 008A	VNT 009A	VNS 009A	UNITS
Drain-Source Voltage		V_{DS}	650	600	650	600	V
Gate-Source Voltage		V_{GS}	± 20	± 20	± 20	± 20	
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	5.77	5.77	5.0	5.0	A
	$T_C = 100^\circ\text{C}$		3.65	3.65	3.16	3.16	
Pulsed Drain Current ¹		I_{DM}	15	15	14	14	
Avalanche Current (See Figure 9)		I_A	5.77	5.77	5.0	5.0	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	125	125	125	125	W
	$T_C = 100^\circ\text{C}$		50	50	50	50	
Operating Junction & Storage Temperature Range	T_J, T_{stg}		-55 to 150				$^\circ\text{C}$
Lead Temperature ($1/16$ " from case for 10 sec.)	T_L		300				

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THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	R_{thJC}		1.0	K/W
Junction-to-Ambient	R_{thJA}		80	
Case-to-Sink	R_{thCS}	1.0		

¹Pulse width limited by maximum junction temperature (refer to transient thermal impedance data, Figure 11).

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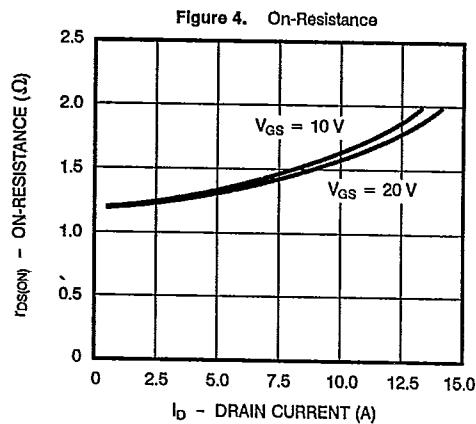
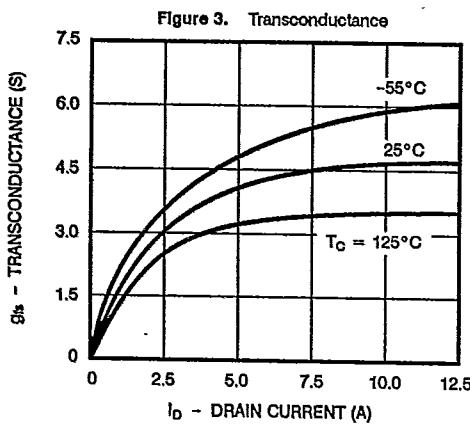
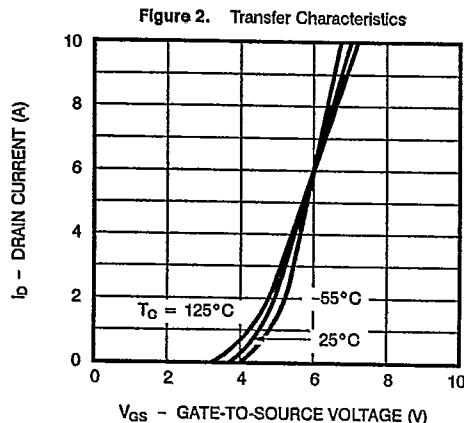
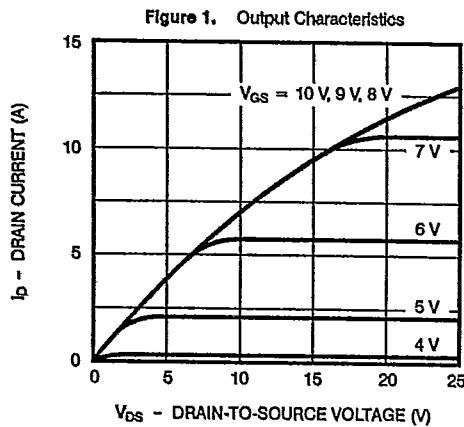
ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	TYP	LIMITS		UNIT
				MIN	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 2000 μA		650	600	V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 1000 μA		2.0	4.0	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = V _{(BR)DSS} , V _{GS} = 0 V			2000	μA
		V _{DS} = 0.8 \times V _{(BR)DSS} , V _{GS} = 0 V, T _J = 125°C			2000	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 10 V, V _{GS} = 10 V		5.7		A
Drain-Source On-State Resistance ¹	r _{D(ON)}	V _{GS} = 10 V, I _D = 3 A	1.2	1.5	2.0	Ω
		V _{GS} = 10 V, I _D = 3 A, T _J = 125°C	2.4	3.75	6.0	
Forward Transconductance ¹	G _f	V _{DS} = 15 V, I _D = 3 A	3.3	3.0		s
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	1200		1500	pF
Output Capacitance	C _{oss}		140		150	
Reverse Transfer Capacitance	C _{rss}		40		50	
Total Gate Charge ²	Q _g	V _{DS} = 0.5 \times V _{(BR)DSS} , V _{GS} = 10 V, I _D = 5.7 A	53		75	nC
Gate-Source Charge ²	Q _{gs}		12.9			
Gate-Drain Charge ²	Q _{gd}		26			
Turn-On Delay Time ²	t _{d(on)}	V _{DD} = 325 V, R _L = 130 Ω I _D \approx 2.5 A, V _{GEN} = 10 V, R _G = 4.7 Ω	15		20	ns
Rise Time ²	t _r		20		25	
Turn-Off Delay Time ²	t _{d(off)}		80		85	
Fall Time ²	t _f		45		50	
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T_C = 25°C)						
Continuous Current	VNT008A, VNS008A VNT009A, VNS009A	I _S			5.77 5.0	A
Pulsed Current ³	VNT008A, VNS008A VNT009A, VNS009A	I _{SM}			15 14	
Forward Voltage ¹	VNT008A, VNS008A VNT009A, VNS009A	V _{SD}	I _F = I _S , V _{GS} = 0 V		2.5 2.0	V
Reverse Recovery Time	t _{rr}	I _F = I _S , dI _F /dt = 100 A/ μ s	400			ns
Reverse Recovery Charge	Q _{rr}		2.5			
					μ C	

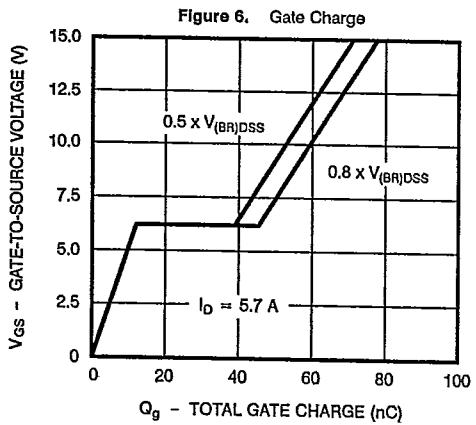
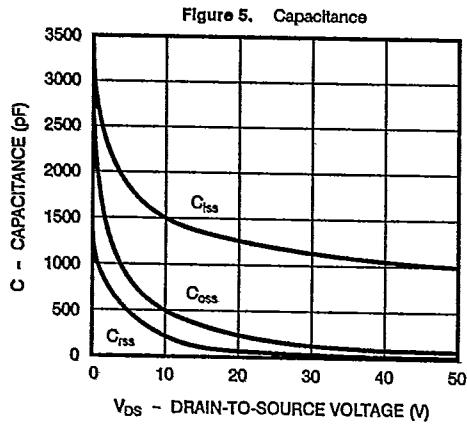
¹Pulse test: Pulse Width \leq 300 μ sec, Duty Cycle \leq 2%.²Independent of operating temperature.³Pulse width limited by maximum junction temperature (refer to transient thermal impedance data, Figure 11).

TYPICAL CHARACTERISTICS (25°C Unless Otherwise Specified)

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TYPICAL CHARACTERISTICS (Cont'd)

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Figure 7. On-Resistance vs. Junction Temperature

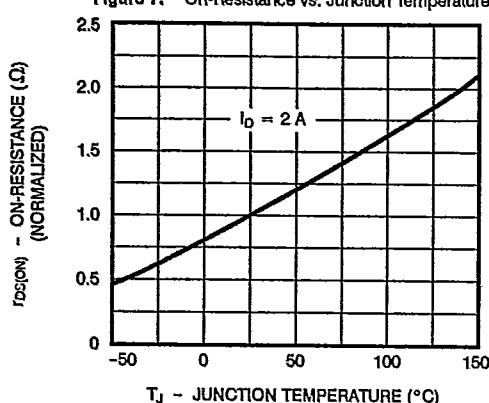
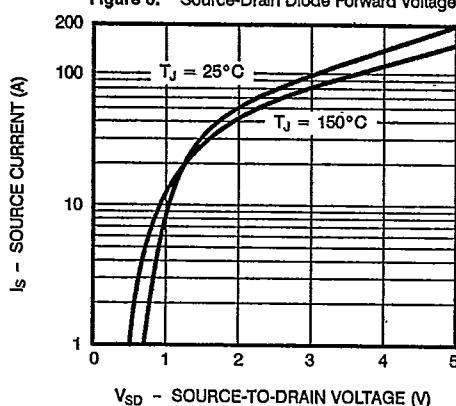


Figure 8. Source-Drain Diode Forward Voltage



THERMAL RATINGS

Figure 9. Maximum Avalanche and Drain Current vs. Case Temperature

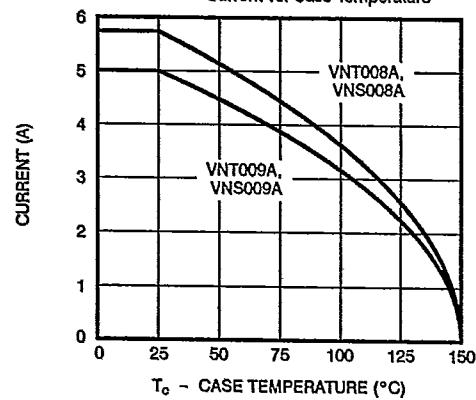


Figure 10. Safe Operating Area

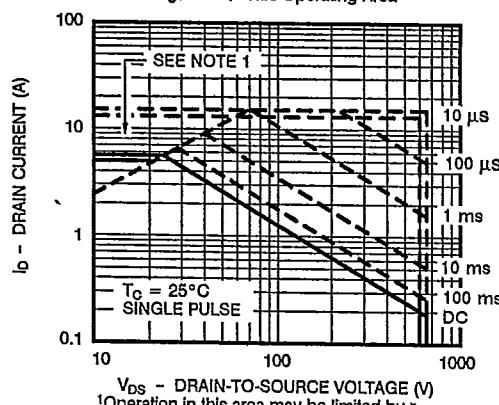


Figure 11. Normalized Effective Transient Thermal Impedance, Junction-to-Case

